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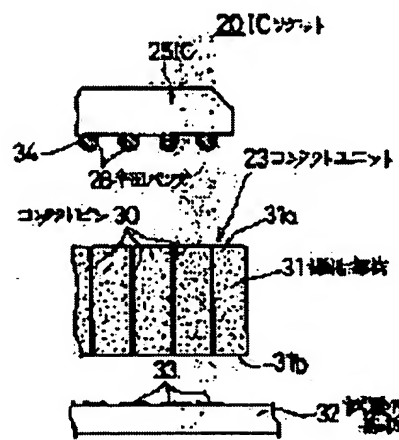
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(54) IC SOCKET, AND TESTING METHOD USING IT, AND MOUNTING MECHANISM OF THE SOCKET

(57)Abstract:

PROBLEM TO BE SOLVED: To carry out a test highly precisely without damaging finely miniaturized and projected electrodes, regarding an IC socket comprising an IC as the testing object, which has the projected electrodes such as bumps, a testing method to be carried out using the IC socket, and a mounting mechanism of the IC socket.

SOLUTION: In the case a test is carried out for an IC 25 which is mounted on a substrate 32 for testing and has solder bumps 28, in the IC socket on which the IC 25 is to be mounted, the lower end part is electrically connected with the substrate 32 for testing and at the same time the upper end part are electrically connected through a contact unit 23 which is constituted of a plurality of linear contact pins 30 to be connected with the solder bumps 28 and an elastic member 31 to support the contact pins 30. The electrical connection of the upper end part is



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carried out by piercing the solder bumps 28 with the end parts of the contact pins 30 whose diameter is made to be fine enough to pierce the solder bumps 28.

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